



PATENT
Customer No. 22,852
Attorney Docket No. 3180.0269.00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
Chie IWASA) Group Art Unit: 2863
Application No.: 09/708,490) Examiner: Lau, Tung S.
Filed: November 9, 2000)
For: SEMICONDUCTOR TESTING METHOD)
AND SEMICONDUCTOR TESTING)
APPARATUS FOR SEMICONDUCTOR)
DEVICES, AND PROGRAM FOR)
EXECUTING SEMICONDUCTOR)
TESTING METHOD)

Commissioner for Patents
Washington, DC 20231

Sir:

RESPONSE

Please consider the following remarks in response to the Office Action dated May 10, 2002. In that action, the Examiner rejected claims 1 – 19 under 35 U.S.C. § 103(a) as unpatentable over U.S. Patent No. 5,694,063 to Burlison et al. (*Burlison*) in view of U.S. Patent No. 4,635,259 to Schinabeck et al. (*Schinabeck*). Applicant traverses this rejection.

In accordance with MPEP § 2143.03, "to establish prima facie obviousness of a claimed invention, all the claim limitations must be taught or suggested by the prior art." Neither of the applied documents, however, taken either singly or in combination, teaches or suggests all the features recited in claims 1-19. Applicant therefore

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